

L Number	Hits	Search Text	DB	Time stamp
37	1461	73/105	USPAT	2003/04/24 15:16
38	1237	((73/105) or (73/606)).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/24 15:17
-	536	(microscope near5 ((atomic or scanning) adj (force or probe))) and (acoustic or ultrasonic or sonic)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/24 11:33
-	0	6389885.URPN.	USPAT	2003/04/24 15:16
-	4	("4030342"   "5319977"   "5675075"   "5852233").PN.	USPAT	2003/04/23 16:23
-	11	("4941753"   "5019707"   "5164791"   "5166516"   "5260824"   "5267471"   "5298975"   "5315373"   "5319977"   "5391871"   "5503010").PN.	USPAT	2003/04/23 16:35
-	181	(microscope near5 ((atomic or scanning) adj (force or probe))) and (acoustic or ultrasonic or sonic) and (mask)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/24 11:59
-	30	(microscope near5 ((atomic or scanning) adj (force or probe))) and (acoustic or ultrasonic or sonic) and (pattern adj recognition)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/24 11:40
-	8	(microscope near5 ((atomic or scanning) adj (force or probe))) and (acoustic or ultrasonic or sonic) and (neural adj network)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/24 11:57
-	30	(microscope near5 ((atomic or scanning) adj (force or probe))) and (acoustic or ultrasonic or sonic) and (mask same align\$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/24 12:31
-	0	"6559926"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/24 12:26
-	214	(microscope near5 ((atomic or scanning) adj (force or probe))) and (mask same align\$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/24 12:32
-	196	((microscope near5 ((atomic or scanning) adj (force or probe))) and (mask same align\$5)) and (semiconductor or wafer or (integrated adj circuit) or ic)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/24 12:33
-	169	((microscope near5 ((atomic or scanning) adj (force or probe))) and (mask same align\$5)) and (semiconductor or wafer or (integrated adj circuit) or ic) ) not ((microscope near5 ((atomic or scanning) adj (force or probe))) and (acoustic or ultrasonic or sonic) and (pattern adj recognition)) or ((microscope near5 ((atomic or scanning) adj (force or probe))) and (acoustic or ultrasonic or sonic) and (mask same align\$5)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/24 12:33

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